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		microscope) and specimen		

	U	1	Document ID	Issue Date	Page s	Title	Current OR
1			US 4672559 A	19870609	16	Method for operating a microscopical mapping system	382/128
2			EP 186490 A	19860702	1	Flying field operation for microscopical mapping system - joystick controlled mapping leaves marks trail moving in unison with stage motion, to remain superimposed on viewed image	

.

	Current XRef	Retrieva l Classif	Inventor	S	С	P	2	3	4	5
1	345/634; 345/781; 348/79; 358/1.18		Jansson, Peter A. et al.	×						
2			JANSSON, P A et al.							

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Birkfellner, W.; Huber, K.; Watzinger, F.; Figl, M.; Wanschitz, F.; Hanel, R.; Rafolt, D.; Ewers, R.; Bergmann, H.; Augmented Reality, 2000. (ISAR 2000). Proceedings. IEEE and ACM International Symposium on , 5-6 Oct. 2000 Pages: 54 - 59

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